

Data sheet acquired from Harris Semiconductor SCHS037B - Revised June 2003

CMOS 8-Stage Static **Bidirectional Parallel/Serial** Input/Output Bus Register

High-Voltage Types (20-Volt Rating)

CD4034B is a static eight-stage parallel-or serial-input parallel-output register. It can be used to:

1) bidirectionally transfer parallel information between two buses, 2) convert serial data to parallel form and direct the parallel data to either of two buses, 3) store (recirculate) parallel data, or 4) accept parallel data from either of two buses and convert that data to serial form. Inputs that control the operations include a single-phase CLOCK (CL), A DATA ENABLE (AE), ASYNCHRO-NOUS/SYNCHRONOUS (A/S), A-BUS-TO-B-BUS/B-BUS-TO-A-BUS (A/B), and PAR-ALLEL/SERIAL (P/S).

Data inputs include 16 bidirectional parallel data lines of which the eight A data lines are inputs (3-state outputs) and the B data lines are outputs (inputs) depending on the signal level on the A/B input. In addition, an input for SERIAL DATA is also provided.

All register stages are D-type master-slave flip-flops with separate master and slave clock inputs generated internally to allow synchronous or asynchronous data transfer from master to slave. Isolation from external noise and the effects of loading is provided by output buffering.

PARALLEL OPERATION

A high P/S input signal allows data transfer into the register via the parallel data lines synchronously with the positive transition of the clock provided the A/S input is low. If the A/S input is high the transfer is independent of the clock. The direction of data flow is controlled by the A/B input. When this signal is high the A data lines are inputs (and B data lines are outputs); a low A/B signal reverses the direction of data flow.

The AE input is an additional feature which allows many registers to feed data to a common bus. The A DATA lines are enabled only when this signal is high.

Data storage through recirculation of data in each register stage is accomplished by making the A/B signal high and the AE signal low.

Applications:

- Parallel Input/Parallel Output. Serial Input/Parallel Output, Serial Input/Serial Output Register
- Shift right/shift left register
- Shift right/shift left with parallel loading
- Address register
- **Buffer register**
- Bus system register with enable parallel lines at bus side
- Double bus register system
- **Up-Down Johnson or ring counter**
- Pseudo-random code generators
- counting, display)
- Frequency and phase comparator

SERIAL OPERATION

A low P/S signal allows serial data to transfer into the register synchronously with the positive transition of the clock. The A/S input is internally disabled when the register is in the serial mode (asynchronous serial operation is not allowed).

The serial data appears as output data on either the B lines (when A/B is high) or the A lines (when A/B is low and the AE signal is high).

Register expansion can be accomplished by simply cascading CD4034B packages.

The CD4034B types are supplied in 24-lead hermetic dual-in-line ceramic packages (F3A suffix), 24-lead dual-in-line plastic packages (E suffix), 24-lead small-outline packages (M, M96, and NSR suffixes), and 24-lead thin shrink small-outline packages (PW and PWR suffixes).

- Features:
- Sample and hold register (storage,

STEERING LOGIC A/5 92CS-29108 Functional Diagram

CD4034B Types

- Bidirectional parallel data input
- Parallel or serial inputs/parallel outputs
- Asynchronous or synchronous parallel data loading
- Parallel data-input enable on "A" data lines (3-state output)
- Data recirculation for register expansion
- Multipackage register expansion
- Fully static operation dc-to-10 MHz (typ.) at V_{DD} = 10 V
- Standardized, symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- 5-V, 10-V, and 15-V parametric ratings
- Maximum input current of 1 µA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range):

1 V at V_{DD} = 5 V

2 V at V_{DD} = 10 V 2.5 V at V_{DD} = 15 V

■ Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

MAXIMUM RATINGS, Absolute-Maximum Values: DC SUPPLY-VOLTAGE RANGE, (VDD)

ages referenced to V _{SS} Terminal)0.5V to +20V	V
VOLTAGE RANGE, ALL INPUTS0.5V to V _{DD} +0.5V	INP
PUT CURRENT, ANY ONE INPUT ±10mA	DC
R DISSIPATION PER PACKAGE (PD):	
T _A = -55°C to +100°C	F
T _A = +100°C to +125°C Derate Linearity at 12mW/°C to 200mW	F
E DISSIPATION PER OUTPUT TRANSISTOR	
TA = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)	F
ATING-TEMPERATURE RANGE (TA)55°C to +125°C	
AGE TEMPERATURE RANGE (Tstg)65°C to +150°C	
TEMPERATURE (DURING SOLDERING):	
stance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max +265°C	Α

RECOMMENDED OPERATING CONDITIONS at $T_A = 25^{\circ}$ C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V _{DD}	LIM	ITS	LINUTE
CHARACTERISTIC	(V)	Min.	Max.	UNITS
Supply-Voltage Range (For $T_A = Full Package-Temperature Range)$		3	18	V
Data Setup Time, t _S	5	160	_	
Serial Data to Clock	10	60	- 1	ns
	15	40		
	5	50		
Parallel Data to Clock	10	30	-	ns
	15	20	_	
	5	350	-	
Clock Pulse Width, t _W	10	140	-	ns
	15	80	_	
	5		2	
Clock Input Frequency, f _{CL}	10	dc	5	MHz
	15		7	
Clock Input Rise or Fall Time, t _f CL, t _f CL*	5, 10, 15	_	15	μs

^{*}If more than one unit is cascaded t_rCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

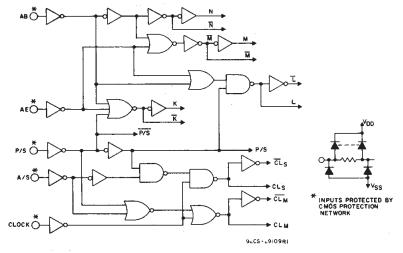


Fig. 1 - Steering logic diagram.

FLIP-FLOP TRUTH TABLE

	INPUTS		OUTPUT
CLM	CLS	D	Q
		0	0
		0	0
	_	0	INVALID
		Х	0
		1	1
		1	1
		1	INVALID

1 = High Level 0 = Low Level X = Don't Care

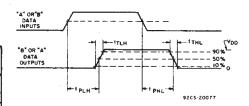
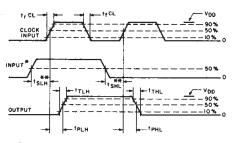


Fig. 2 — Asynchronous operation propagation delay time and transition time.



- * INPUT REFERS TO ANY OF THE "A"OR "B" DATA INPUTS, "A"ENABLE, SERIAL INPUT, A/B, P/S, OR A/S INPUTS
- ** TSLH AND TSHL ARE SET-UP TIMES

Fig. 3 — Synchronous operation propagation delay times, transition times, and set-up times.

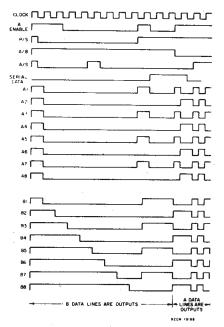


Fig. 4 - Timing diagram.

STATIC ELECTR	CAL CHA	RACTERISTICS
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CHARAC- TERISTIC	CON	DITIO	NS	Lir	MITS AT	INDICAT	ED TEM	PERAT	URE\$ (°	C)	U N – T
	v _O	VIN	V _{DD}						+25		S
	(V)	(V)	(V)	-55	40	+85	+125	Min.	Тур.	Max.	
Quiescent		0,5	5	5	5	150	150		0.04	5	
Device		0,10	10	10	10	300	300	_	0.04	10	μΑ
Current,		0,15	15	20	20	600	600		0.04	20	
55	-	0,20	20	100	100	3000	3000		0.08	100	
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	_	
(Sink) Current	0.5	0,10	10	1.6	- 1.5	1.1	0.9	1.3	2.6	-	
IOL Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	_	
Output High	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	_1	_	mΑ
(Source)	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-	
Current,	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	-	
IOH Min.	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	-	
Output Voltage:		0,5	5	0.05 _					0	0.05	
Low-Level,	_	0,10	10		0	.05		0	0.05		
VOL Max.		0,15	15	0.05				-	0	0.05	$ _{\mathbf{v}} $
Output	. —	0,5	- 5	4.95 4.95 5					_		
Voltage: High-Level,	_	0,10	10		9	.95	9.95	10	_		
VOH Min.	-	0,15	15		14	14.95	15	_			
Input Low	0.5,4.5		5			1.5		_	_	1.5	
Voltage	1,9	_	10			3		_	_	3	
VIL Max.	1.5,13.5	_	15				_	4	l v		
Input High	0.5,4.5	_	5		3	3.5		3.5			
Voltage,	1,9	_	10		, , , , ,	7		7	_	-	
V _{IH} Min.	1.5,13.5	_	15		•	11		11	_	-	
Input Current *	_	0,18	18	±0.1	±0.1	±1	±1		±10 ⁻⁵	±0.1	μΑ
3-State Output Leakage Current IOUT Max.	0,18	0,18	18	±0.4	±0.4	±12	±12)	±10 ⁻⁴	±0.4	μΑ

AMBIENT TEMPERATURE (TA)=25°C

TEMPERATURE (T

Fig. 5 — Typical output low (sink) current characteristics.

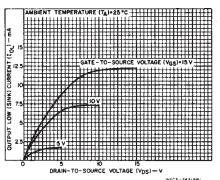


Fig. 6 - Minimum output low (sink) current characteristics.

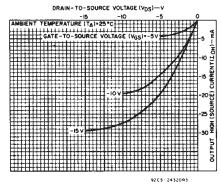


Fig. 7 — Typical output high (source) current characteristics.

^{*} All inputs except A and B Lines.

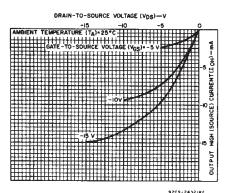


Fig. 8 — Minimum output high (source)

current characteristics.

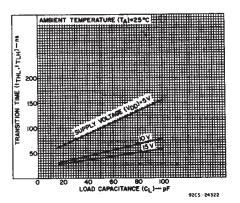


Fig. 9 — Typical transition time as a function of load capacitance.

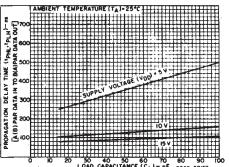


Fig. 10 — Typical propagation delay time as a function of load capacitance (A(B) parallel Data Input to B(A) parallel Data Output, synchronous or asynchronous].

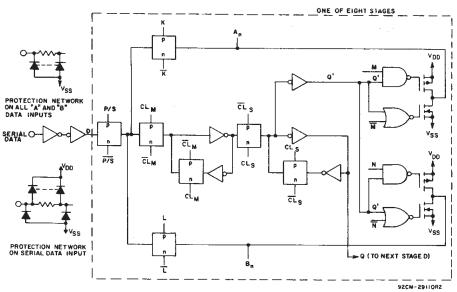


Fig. 11 - Register stage logic diagram (1 of 8 stages).

TRUTH TABLE FOR REGISTER INPUT-LEVELS AND RESULTING REGISTER OPERATION

"A" Enable	P/S	A/B	A/S	Operation*
0	0	0	х	Serial Mode; Synch. Serial Data Input, "A" Parallel Data Outputs Disabled
0	0	1	Х	Serial Mode; Synch. Serial Data Input, "B" Parallel Data Output
0	1	0	0	Parallel Mode; "B" Synch. Parallel Data Inputs, "A" Parallel Data Outputs Disabled
0	1	0	1	Parallel Mode; "B" Asynch. Parallel Data Inputs, "A" Parallel Data Outputs Disabled
0	1	1	0	Parallel Mode; "A" Parallel Data Inputs Disabled, "B" Parallel Data Outputs, Synch. Data Recirculation
0	1	1	1	Parallel Mode; "A" Parallel Data Inputs Disabled, "B" Parallel Data Outputs, Asynch. Data Recirculation
1	0	0	Х	Serial Mode; Synch. Serial Data Input, "A" Parallel Data Output
1	0	1	Х	Serial Mode; Synch. Serial Data Input, "B" Parallel Data Output
1	1	0	0	Parallel Mode; "B" Synch. Parallel Data Input, "A" Parallel Data Output
1	1	0	1	Parallel Mode; "B" Asynch. Parallel Data Input, "A" Parallel Data Output
1	1	1	0	Parallel Mode; "A" Synch. Parallel Data Input, "B" Parallel Data Output
1	1	1	1	Parallel Mode; "A" Asynch. Parallel Data Input, "B" Parallel Data Output

^{*}Outputs change at positive transition of clock in the serial mode and when the A/S control input is "low" in the parallel mode. During transfer from parallel to serial operation A/S should remain low in order to prevent D_S transfer into Flip Flops.

1 = HIGH LEVEL

0 = LOW LEVEL

X = DON'T CARE

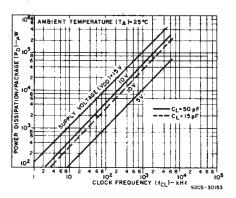


Fig. 12 — Typical dynamic power dissipation as a function of clock frequency.

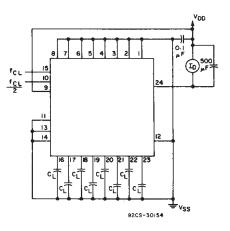


Fig. 13 — Dynamic power dissipation test circuit.

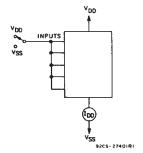


Fig. 14 - Quiescent-device-current test circuit.

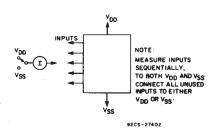


Fig. 15 - Input-current test circuit.

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25^{\circ}C$; Input $t_r, t_t = 20 \text{ ns}$,

 $C_L = 50 pF$, $R_L = 200 k\Omega$

CHARACTERISTIC	V _{DÓ} (V)		LIMITS		UNITS
CHARACTERISTIC	ADD (A)	MIN.	TYP.	MAX.	UNITS
Propagation Delay Time, tehl, tell	н 5	-	350	700	
A(B) Parallel Data in to	10	-	120	240	İ
B(A) Parallel Data Out	15	-	85	170	1
Serial to Parallel Data Out	1				
3-State Propagation Delay tplz,tphz	5		200	400	1
A/B or AE to "A" OUT tpzL, tpzL	10	-	80	160	
	15	-	60	120	
Transition Time, tthi, ttl.	1 5	_	100	200	1
	10	-	50	100	İ
	15	l –	40	80	
Minimum Data Setup Time, tsu	5		80	160	1
Serial Data to Clock	10	-	30	60	ns
	. 15	-	20	40	
-	5	-	25	50	1
Parallel Data to Clock	10		15	30	
	15	-	10	. 20	
Minimum Data Hold Time, t _H	5	—		50	1
	10	-	-	15	
	15	-	-	10	
Minimum High-Level	5	 -	175	350	1
Pulse Width, tw	10	-	70	140	
AE, P/S, A/S	15	-	40	80	i
Maximum Clock	5	2	4	_	
Frequency, f _{CL}	10	5	10	-	MHz
	15	7	14	-	
Minimum Clock Pulse	5		125	250	
Width, tw	10	-	50	100	ns
	15	-	35	70	' '
Maximum Clock Rise or Fall Time, t,CL, t,C	5,10,15	-	_	15	μs
Input Capacitance, Cin	Any Input	 	5	7.5	pF

92CS-2744IRI
Fig. 16 — Input-voltage test circuit.

Applications

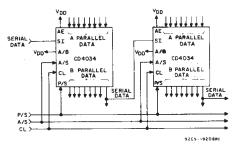
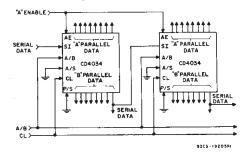
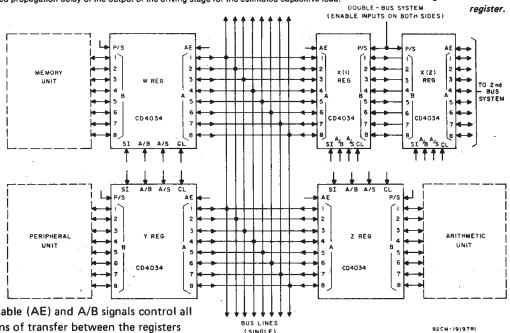


Fig. 17 — 16-bit parallel in/parallel out, parallel in/serial out, serial in/ parallel out, serial in/serial out register.



*If more than one unit is cascaded tCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

Fig. 18 — 16-bit serial in/gated parallel out



The "A" enable (AE) and A/B signals control all combinations of transfer between the registers and bus systems.

Fig. 19 - Single- and double-bus systems.

VOD

INPUTS

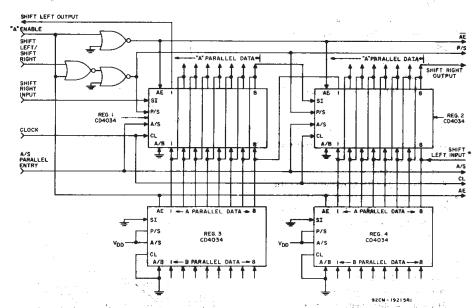
OUTPUTS

OUTPUTS

VIL

NOTE:

TEST ANY COMBINATION
OF INPUTS



A "High" ("Low") on the shift Left/Shift Right input allows serial data on the Shift Left Input (Shift Right Input) to enter the register on the positive transition of the clock signal. A "high" on the "A" Enable Input disables the "A" parallel data lines on Reg. 1 and 2 and enables the "A" data lines on registers 3 and 4 and allows parallel data

into registers 1 and 2. Other logic schemes may be used in place of registers 3 and 4 for parallel loading.

When parallel inputs are not used Reg. 3 and 4 and associated logic are not required.

Fig. 20 - Shift right/shift left with parallel inputs.

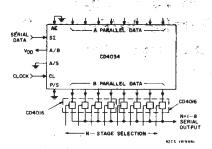


Fig. 21 — N-stage shift register with fixed serial output line.

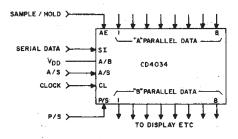
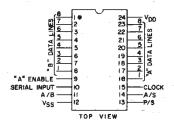
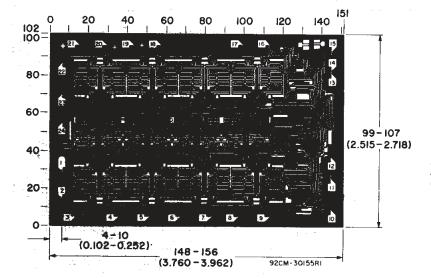


Fig. 22 — Sample and hold register—serial/ parallel in—parallel out.



TERMINAL DIAGRAM

9205-20744RI



Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

Dimensions and pad layout for CD4034BH.

^{*} Shift left input must be disabled during parallel entry.







10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD4034BF3A	ACTIVE	CDIP	J	24	1	Non-RoHS & Non-Green	Call TI	N / A for Pkg Type	-55 to 125	CD4034BF3A	Samples
CD4034BM	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4034BM	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

10-Dec-2020

OTHER QUALIFIED VERSIONS OF CD4034B, CD4034B-MIL:

• Military: CD4034B-MIL

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 5-Jan-2022

TUBE



*All dimensions are nominal

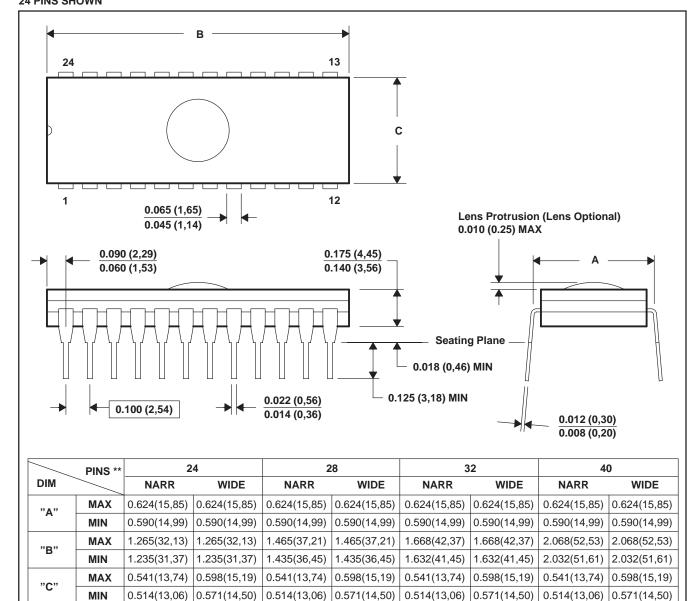
Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CD4034BM	DW	SOIC	24	25	506.98	12.7	4826	6.6

4040084/C 10/97

J (R-GDIP-T**)

24 PINS SHOWN

CERAMIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Window (lens) added to this group of packages (24-, 28-, 32-, 40-pin).
- D. This package can be hermetically sealed with a ceramic lid using glass frit.
- E. Index point is provided on cap for terminal identification.



DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



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